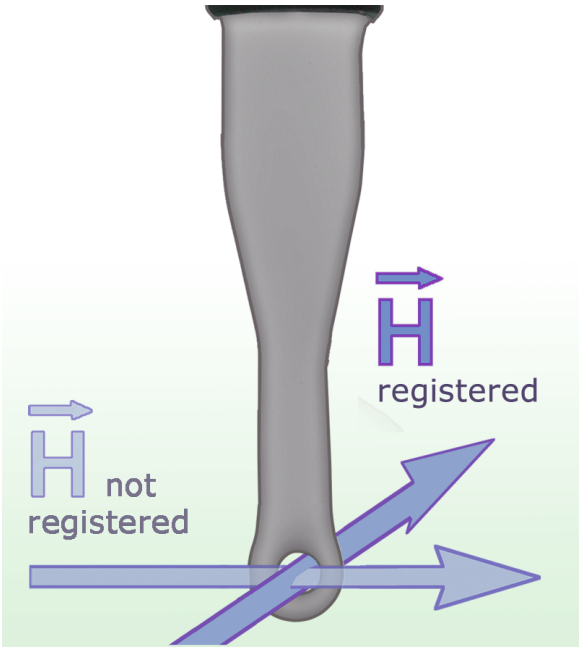
XFS-R 3-1

Scanner Probe 30 MHz up to 6 GHz



Short description

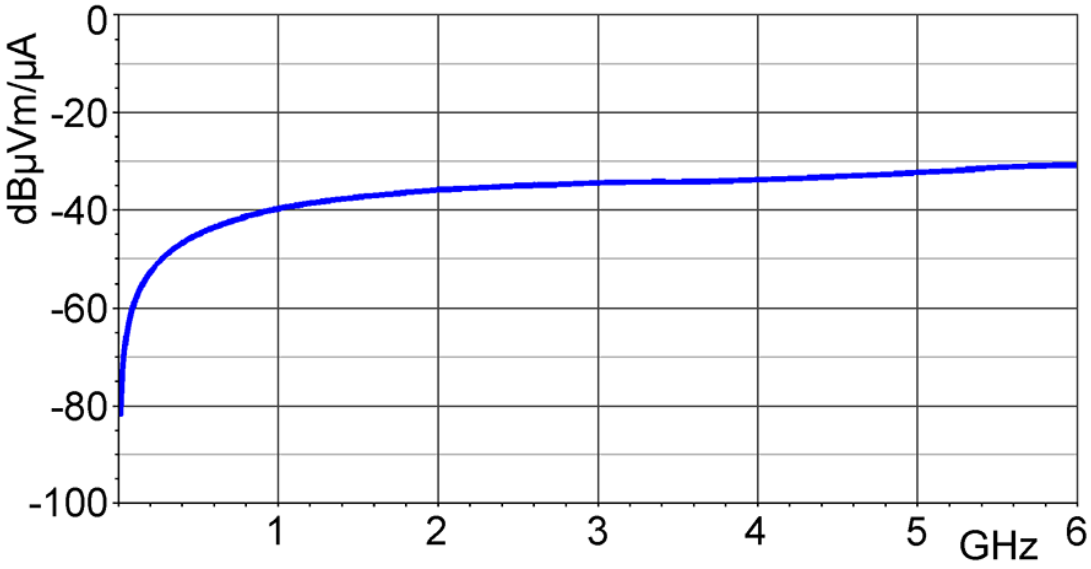
The XFS-R 3-1 scanner probe is designed for direct high-resolution measurements of RF magnetic fields on an assembly, e.g. around the pins and IC cases, conducting paths, decoupling capacitor, and EMC components.

The XFS-R 3-1 H-field scanner probe is suitable for measurements close to the components with high magnetic field strength. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe has an internal terminating resistance.

Technical parameters

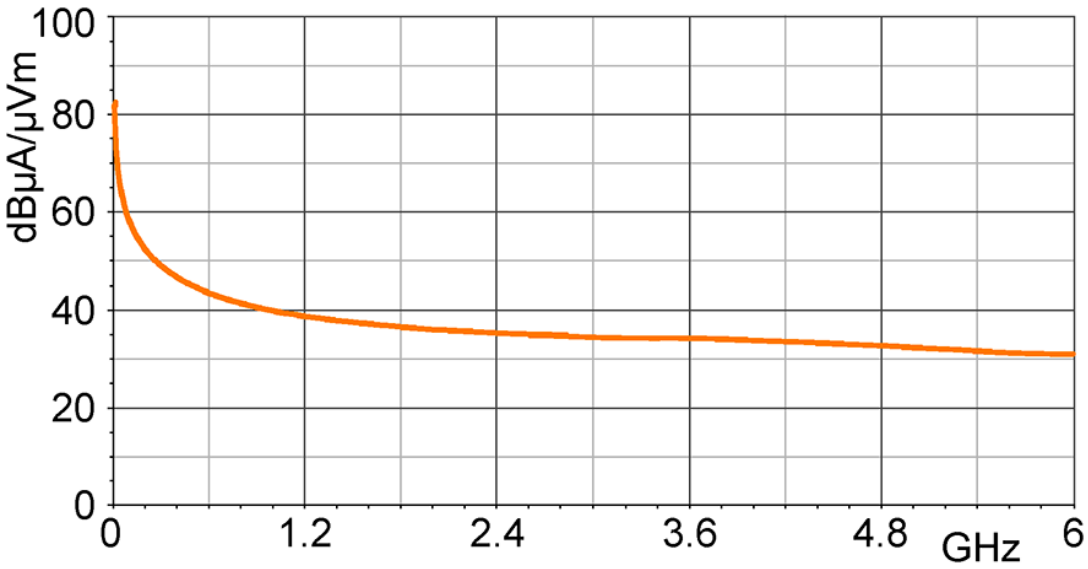
Frequency range	30 MHz ... 6 GHz
Resolution	≈ 1 mm
Probe head dimensions	Ø ≈ 3 mm
Connector - output	SMA, male, jack

Frequency response [dBµV] / [dBµA/m]

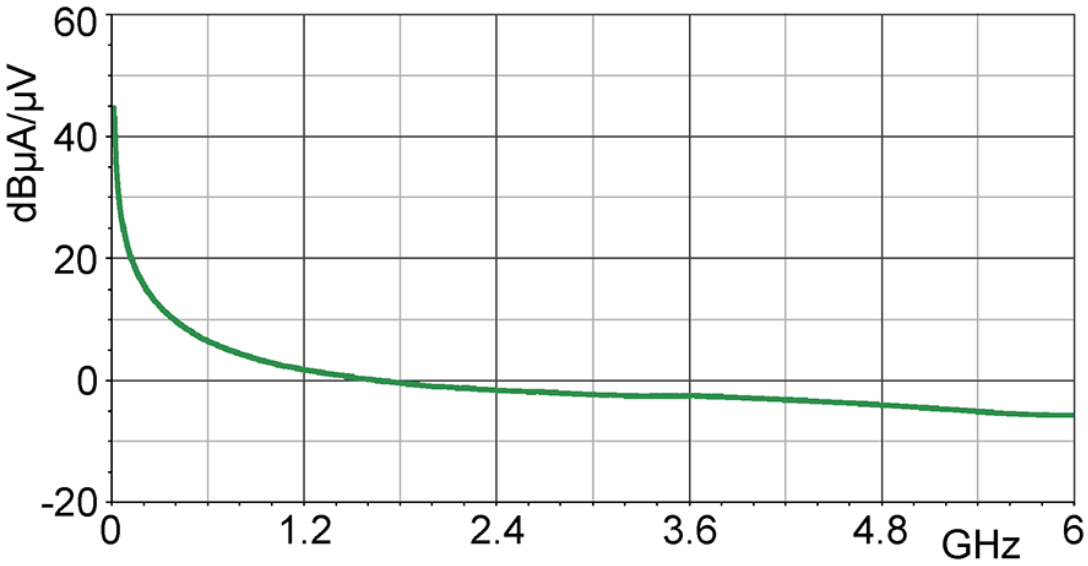


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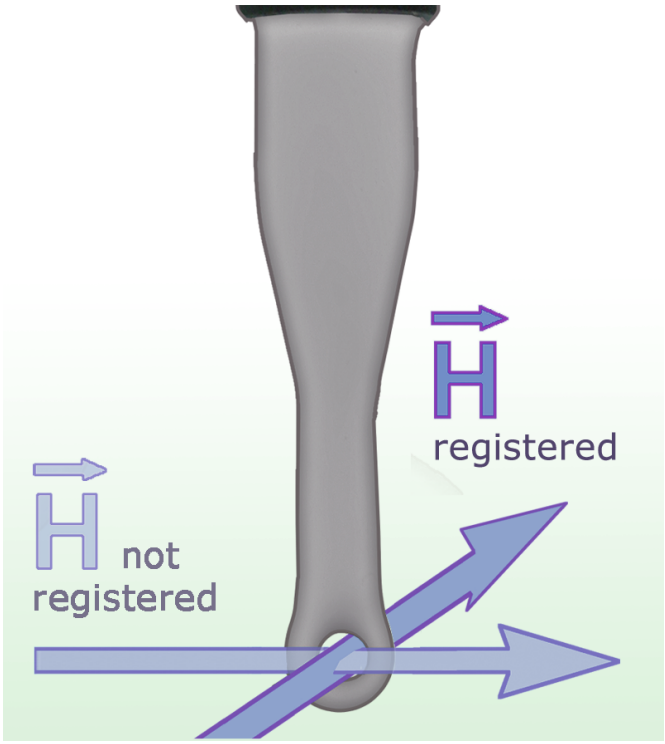
H-field correction curve [dBµA/m] / [dBµV]



Current correction curve [dBµA] / [dBµV]



Measuring principles





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